

L Number	Hits	Search Text	DB	Time stamp
1	1079	700/121.ccls.	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/13 22:43
2	218	700/121.ccls. and (delay or hysteresis)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/13 22:51
3	210	700/121.ccls. and (delay or hysteresis)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/13 22:44
4	218	(700/121.ccls. and (delay or hysteresis)) or (700/121.ccls. and (delay or hysteresis))	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/13 22:44
5	176	((700/121.ccls. and (delay or hysteresis)) or (700/121.ccls. and (delay or hysteresis))) and wafer	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/13 22:57
6	111	((((700/121.ccls. and (delay or hysteresis)) or (700/121.ccls. and (delay or hysteresis))) and wafer) and (model\$5 or simulat\$5 or emulat\$5)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/13 22:57
7	27	((((700/121.ccls. and (delay or hysteresis)) or (700/121.ccls. and (delay or hysteresis))) and wafer) and (model\$5 or simulat\$5 or emulat\$5)) and (voltage and current)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/13 22:52
8	4	((((700/121.ccls. and (delay or hysteresis)) or (700/121.ccls. and (delay or hysteresis))) and wafer) and (model\$5 or simulat\$5 or emulat\$5)) and (threshold with voltage)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/13 22:57
9	95	700/108.ccls. and (delay or hysteresis)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/13 22:57
10	93	700/108.ccls. and (delay or hysteresis)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/13 22:52
11	95	(700/108.ccls. and (delay or hysteresis)) or (700/108.ccls. and (delay or hysteresis))	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/13 22:52
12	34	((700/108.ccls. and (delay or hysteresis)) or (700/108.ccls. and (delay or hysteresis))) and wafer	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/13 22:52
13	24	((((700/108.ccls. and (delay or hysteresis)) or (700/108.ccls. and (delay or hysteresis))) and wafer) and (model\$5 or simulat\$5 or emulat\$5)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/13 22:52
14	7	((((700/108.ccls. and (delay or hysteresis)) or (700/108.ccls. and (delay or hysteresis))) and wafer) and (model\$5 or simulat\$5 or emulat\$5)) and (voltage and current)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/13 22:52
15	2	((((700/108.ccls. and (delay or hysteresis)) or (700/108.ccls. and (delay or hysteresis))) and wafer) and (model\$5 or simulat\$5 or emulat\$5)) and (threshold with voltage)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/13 22:52
16	50	700/109.ccls. and (delay or hysteresis or hysteresis)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/13 22:58

17	18	(700/109.ccls. and (delay or hysteresis or hysteresis)) and wafer	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/13 22:58
18	13	((700/109.ccls. and (delay or hysteresis or hysteresis)) and wafer) and (model\$5 or simulat\$5 or emulat\$5)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/13 22:58
19	0	((700/109.ccls. and (delay or hysteresis or hysteresis)) and wafer) and (model\$5 or simulat\$5 or emulat\$5)) and (threshold with voltage)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/13 22:58
20	50	700/110.ccls. and (delay or hysteresis or hysteresis)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/13 22:58
21	19	(700/110.ccls. and (delay or hysteresis or hysteresis)) and wafer	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/13 22:58
22	11	((700/110.ccls. and (delay or hysteresis or hysteresis)) and wafer) and (model\$5 or simulat\$5 or emulat\$5)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/13 22:58
23	2	((700/110.ccls. and (delay or hysteresis or hysteresis)) and wafer) and (model\$5 or simulat\$5 or emulat\$5)) and (threshold with voltage)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/13 22:58
-	2	((BERTSCH-JOHN-E BERTSCH-JOHN-EDWARD BERTSCH-JOHN COOPS-DANIEL-S FRIED-DAVID FRIED-DAVID-M).in.) and (simulat\$5 or emulat\$5)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/01 10:29
-	43	(BERTSCH-JOHN-E BERTSCH-JOHN-EDWARD BERTSCH-JOHN COOPS-DANIEL-S FRIED-DAVID FRIED-DAVID-M).in.	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/09/30 12:08
-	1	(model same hardware same correlation) and MHC	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/01 10:29
-	140	model same hardware same correlation	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/01 10:30
-	21	model with hardware with correlation	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/01 10:38
-	11	model near3 hardware near3 correlation	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/01 10:52
-	659	wafer with final with test	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/01 10:52
-	223	(wafer with final with test) and (line with test)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/01 10:57
-	91	(wafer with final with test) and (in with line with test)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/01 10:57
-	1	(model same hardware same correlation) and ((wafer with final with test) and (in with line with test))	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/01 11:22
-	1581	(mos or cmos or mosfet) same (verify or verification or verifying)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/01 11:23

-	248	((mos or cmos or mosfet) same (verify or verification or verifying)) and wafer	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/01 11:24
-	8	((((mos or cmos or mosfet) same (verify or verification or verifying)) and wafer) and (source adj current) and (drain adj current)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/01 11:40
-	89	((((mos or cmos or mosfet) same (verify or verification or verifying)) and wafer) and (source with current) and (drain with current)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/01 11:26
-	3	((((mos or cmos or mosfet) same (verify or verification or verifying)) and wafer) and (source with current) and (drain with current)) and (AC or (alternating adj current))	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/01 11:27
-	3	(((((mos or cmos or mosfet) same (verify or verification or verifying)) and wafer) and (source with current) and (drain with current)) and (AC or (alternating adj current))) and (DC or (direct adj current))	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/01 11:27
-	15	((mos or cmos or mosfet) same (verify or verification or verifying)) and wafer) and (spice)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/01 17:00
-	93	(spice and wafer and model and (test or verif\$7) and parameter) and @ad<20010529	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/01 17:01
-	151	spice and wafer and model and (test or verif\$7) and parameter	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/12 13:44
-	5	spice and wafer and model and (test or verif\$7) and parameter and 702/\$3.ccls.	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/06 17:07
-	185	spice and (wafer and model) and (test or verif\$7)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/12 13:45
-	39	spice and ((wafer and model) same (test or verif\$7))	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/12 13:45
-	1	spice and wafer and model and (test or verif\$7) and kerf	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/13 18:02
-	23	kerf same oscillator	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/13 22:43